

Differential Imaging Microscopy of Physically Complex Surfaces Undergoing Atmospheric Corrosion

David G. Enos and Gerald R. Girard
Sandia National Laboratories
Albuquerque, NM 87185

March 16th, 2011

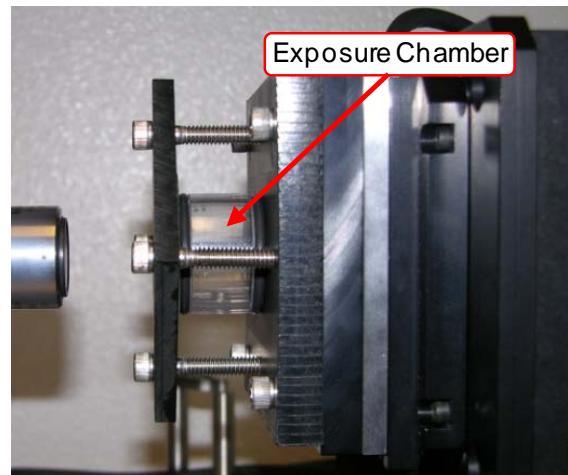
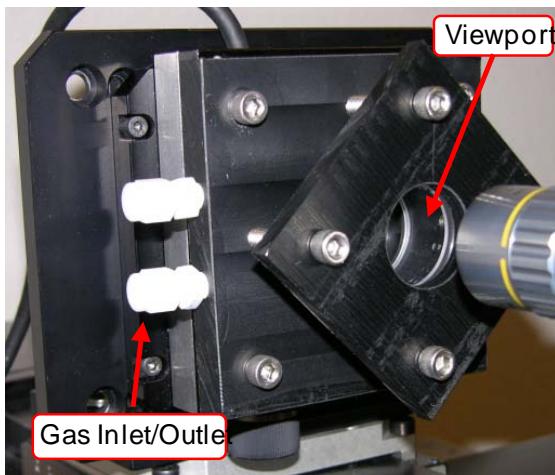
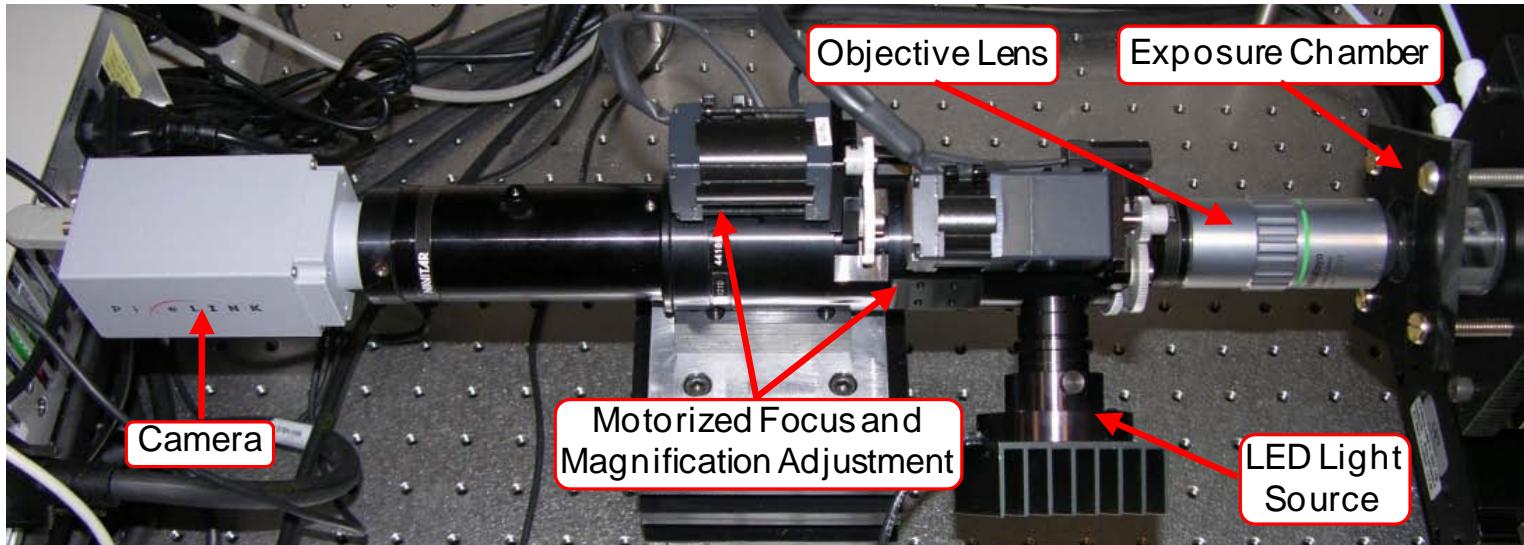
Sandia National Laboratories is a multiprogram laboratory managed and operated by Sandia Corporation, a wholly owned subsidiary of Lockheed Martin Corporation, for the United States Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.



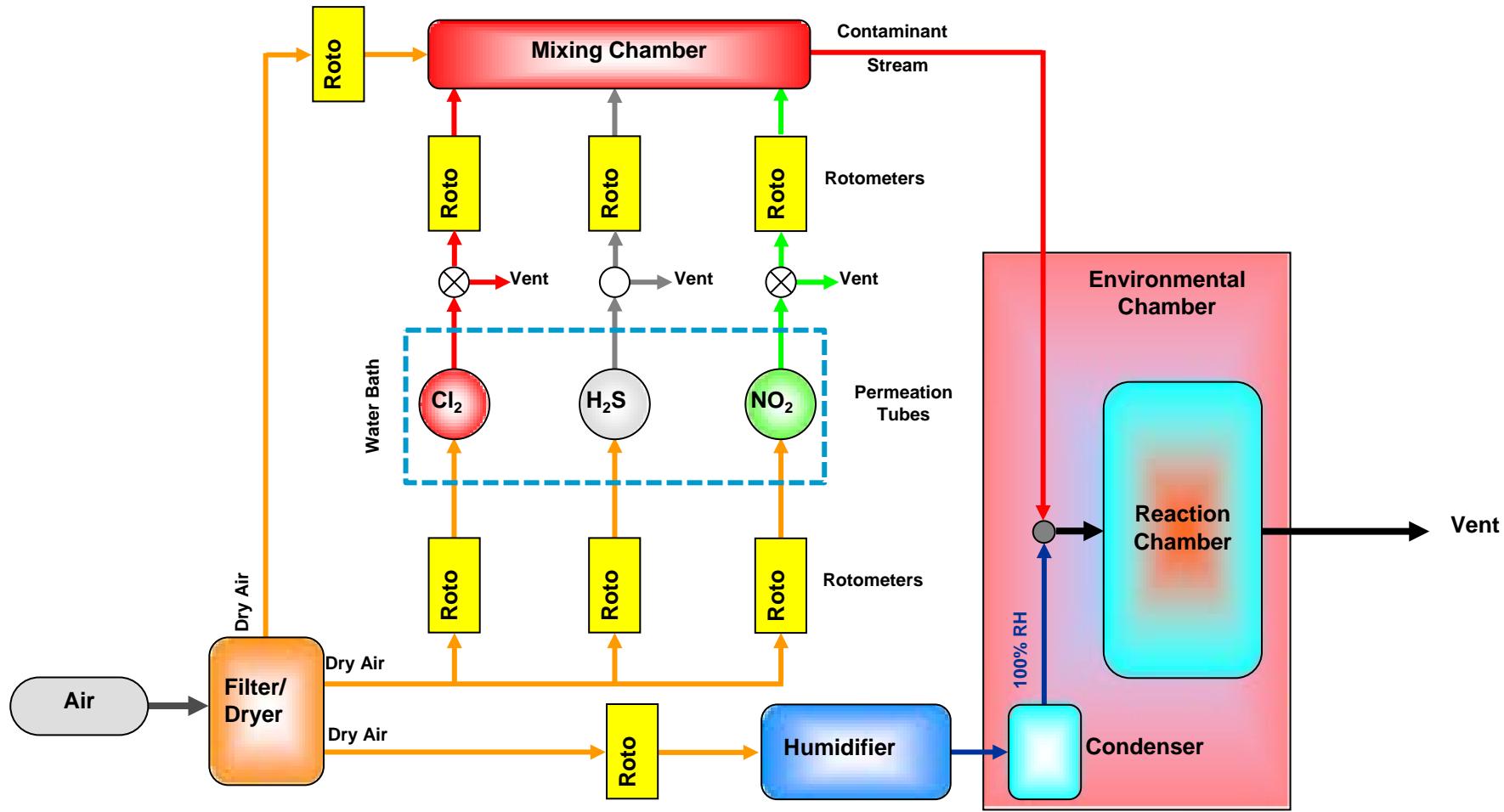
Background

- **Differential imaging technique for in-situ observation of atmospheric corrosion**
 - Similar to work of Isaacs, et. al (2006) for aqueous samples
 - System consists of imaging hardware/optics along with data acquisition and image analysis software
- **Demonstration of system capabilities performed on noble metal plated copper specimens, simulating metallurgies commonly used in microelectronic connectors**

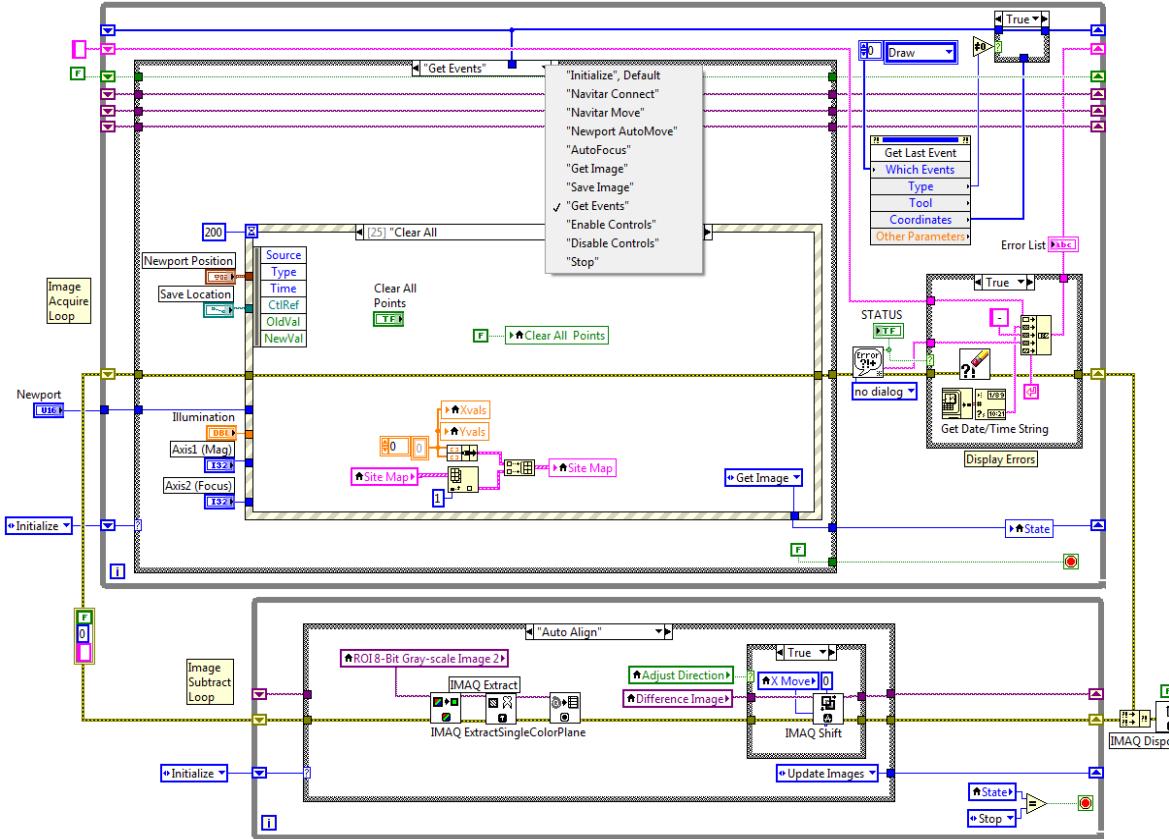
Differential Imaging System Hardware Configuration



Environmental Control – Mixed Flowing Gas System

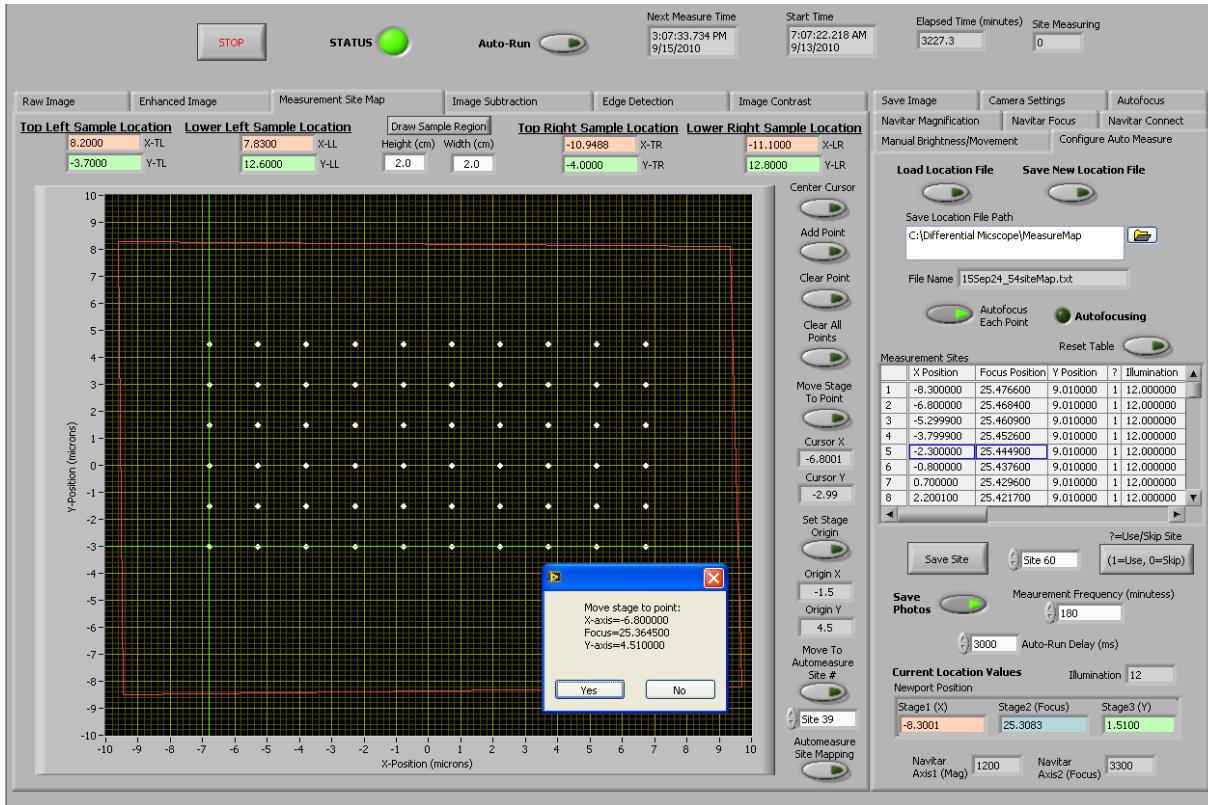


Data Acquisition and Image Analysis Software



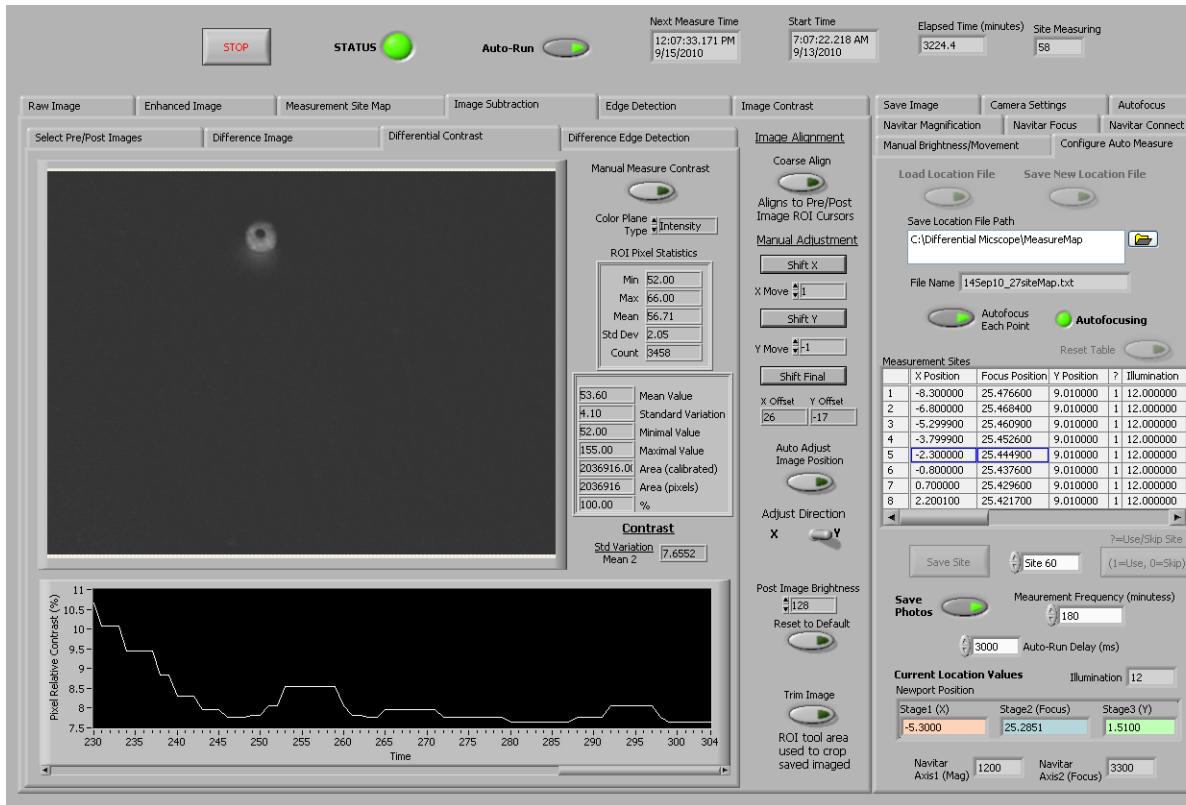
- Code written in NI LabView 2010 and Vision Development Module
- State machine design

Data Acquisition and Image Analysis Software



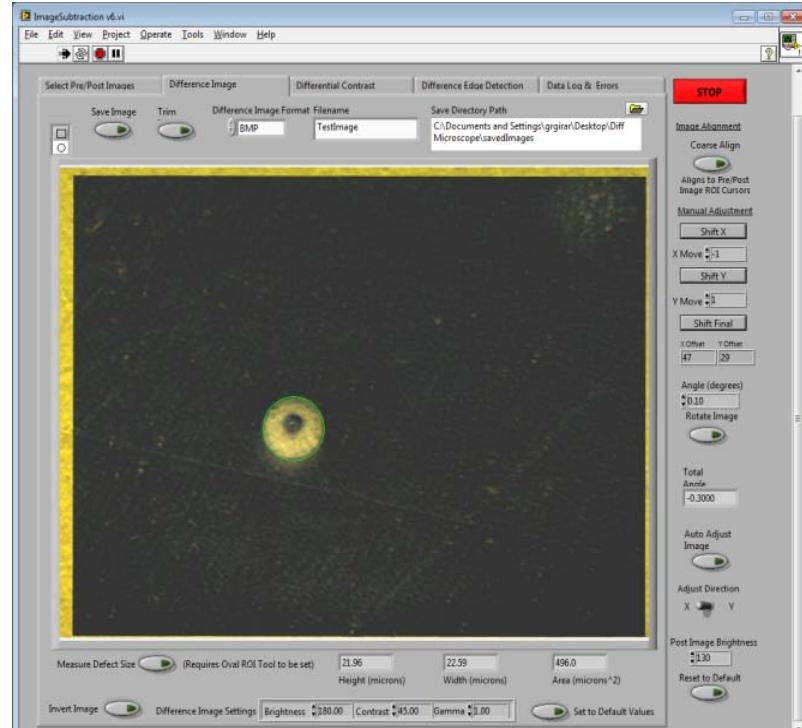
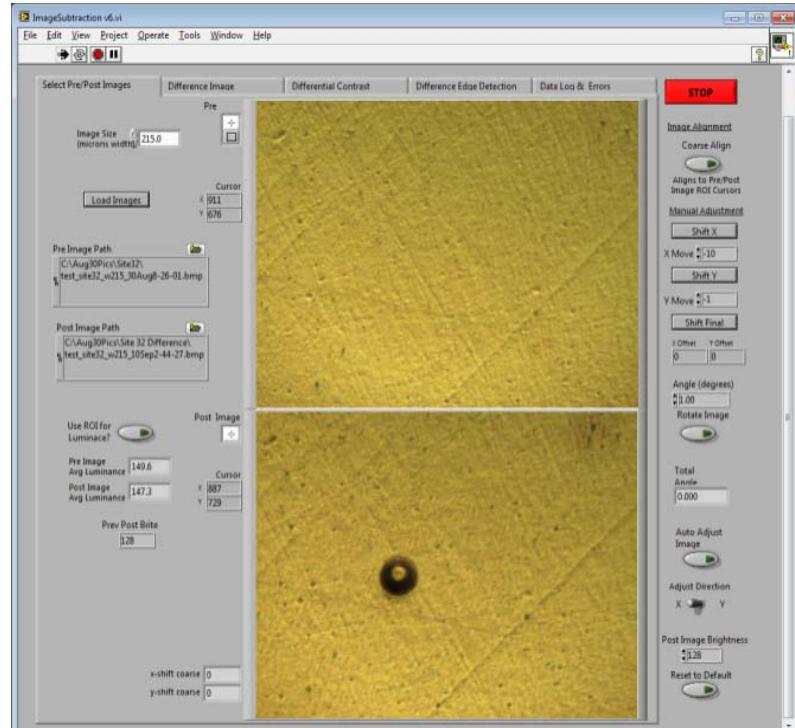
- **Multiple sites**
- **Mapping capability with minimal stage backlash/rotation**
- **Autofocus using Fast Fourier Transform technique**

Data Acquisition and Image Analysis Software

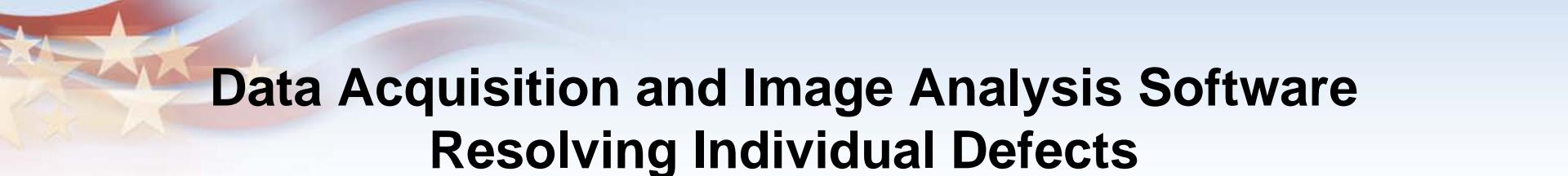


- **Integrated and standalone differential image analysis modules**
 - Semi-automated image alignment
 - Differential contrast used to verify/establish optimum alignment

Data Acquisition and Image Analysis Software

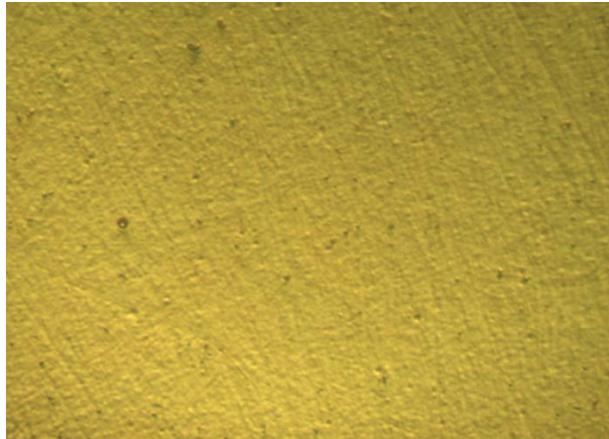


- Pre and post (or live) images combined to form difference image
- Measurement utility to quantify defect size

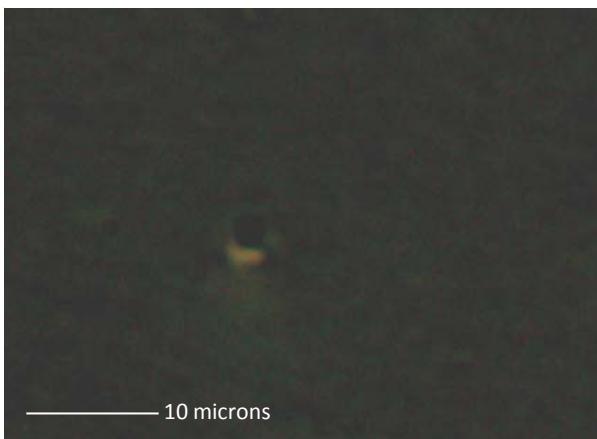
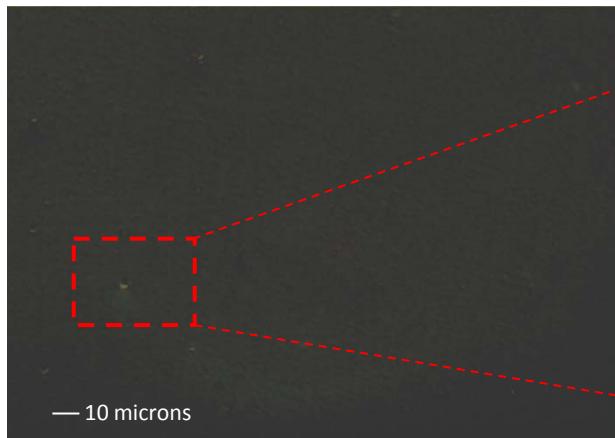
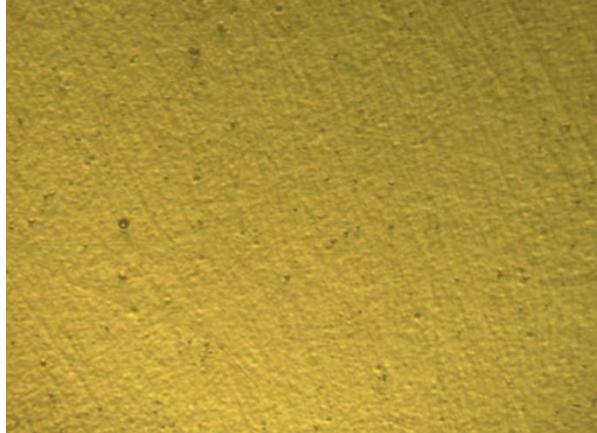


Data Acquisition and Image Analysis Software

Resolving Individual Defects

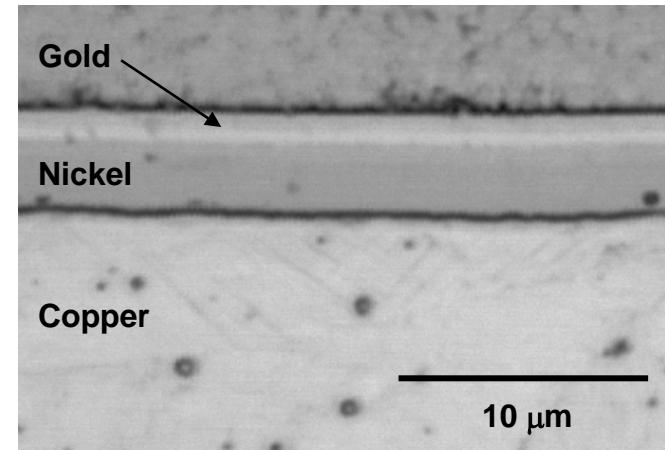
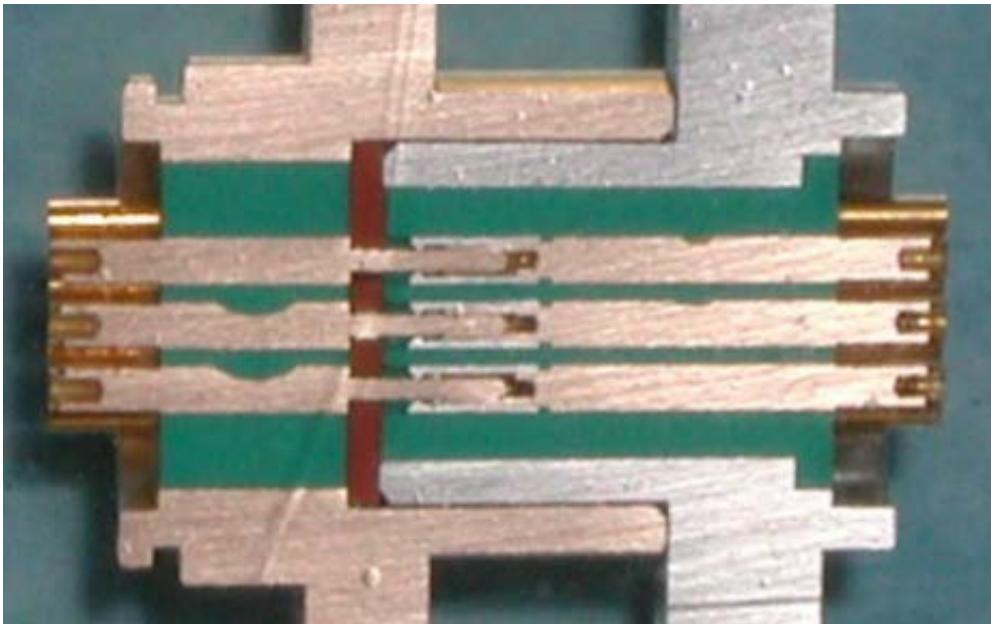


Time →





System Demonstration: Atmospheric Corrosion of Connector Materials



- Atmospheric corrosion of gold plated copper features used in electrical and electronic devices can impact their reliability and effective service life.
- Effective modeling requires that the relevant corrosion degradation phenomena be understood and the key kinetic parameters determined



System Demonstration: Atmospheric Corrosion of Connector Materials

- Oxygen free copper panels, mechanically lapped to a 15-20nm RMS finish
- Electroplated with one of two metallurgies
 - 2.5 μm Au (ASTM Type I, Code C, class 2.5)
 - 2.5 μm Au over 5 μm Ni

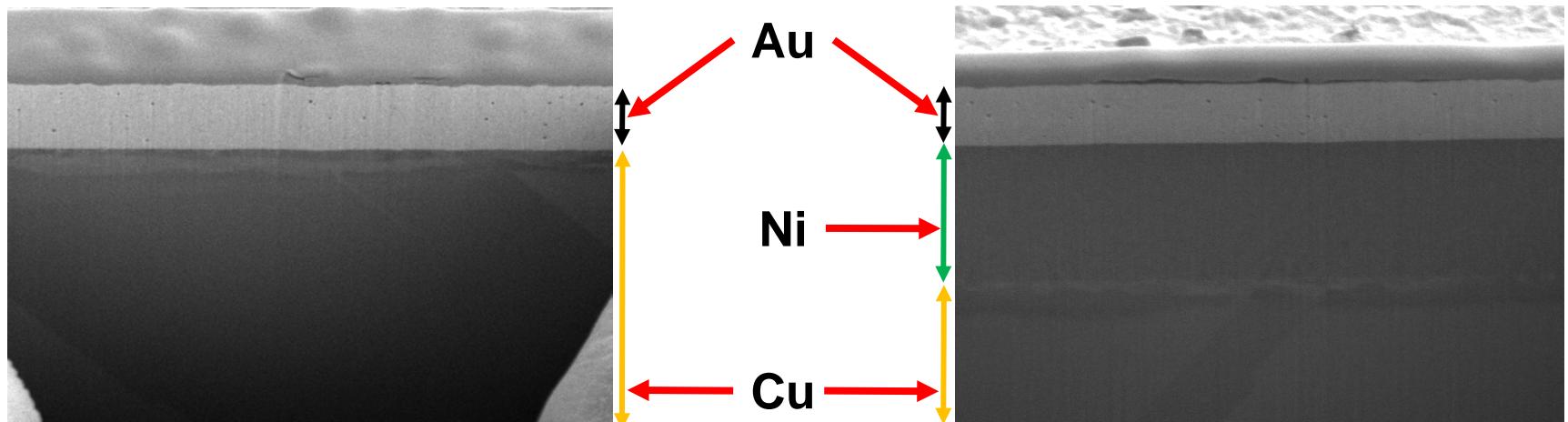
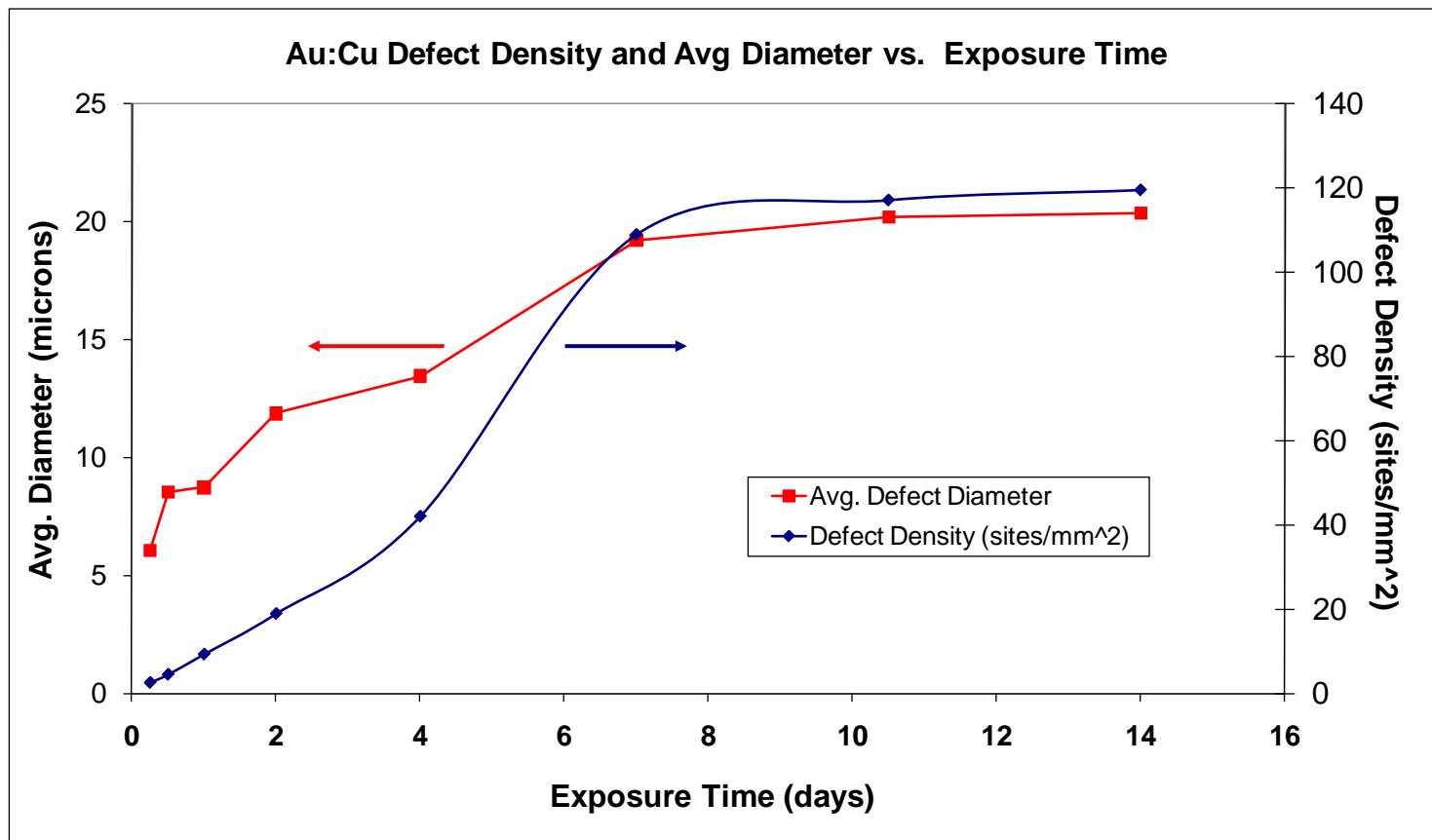
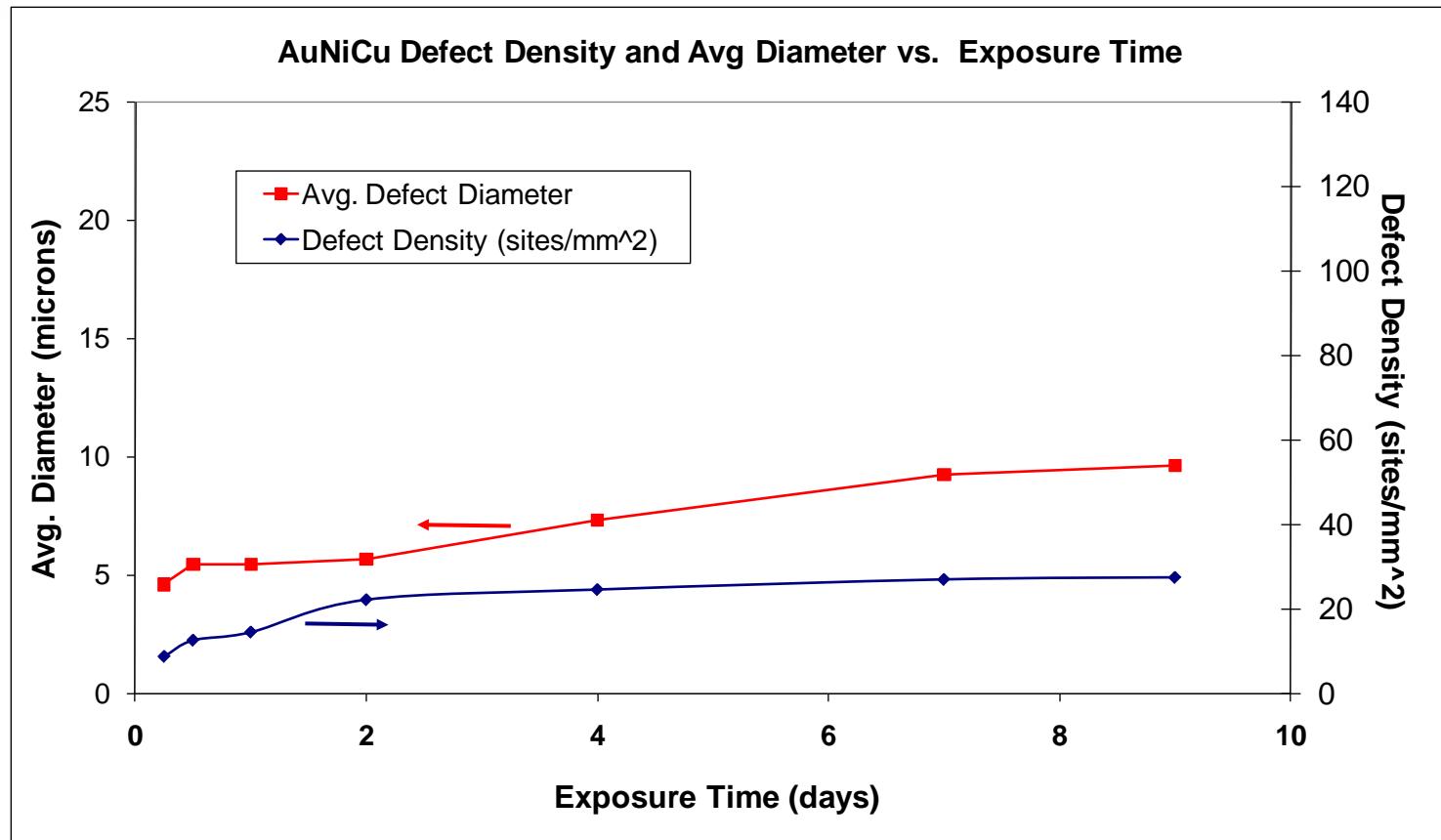


Image Analysis – Defect Density vs. Time Au:Cu Samples



- 60 discrete regions monitored as a function of time
- Defect size approximated as a circle

Image Analysis – Defect Density vs. Time Au:Ni:Cu Samples



- 60 discrete regions monitored as a function of time
- Defect size approximated as a circle

Image Analysis – Defect Size Distribution vs. Time Au:Cu Samples

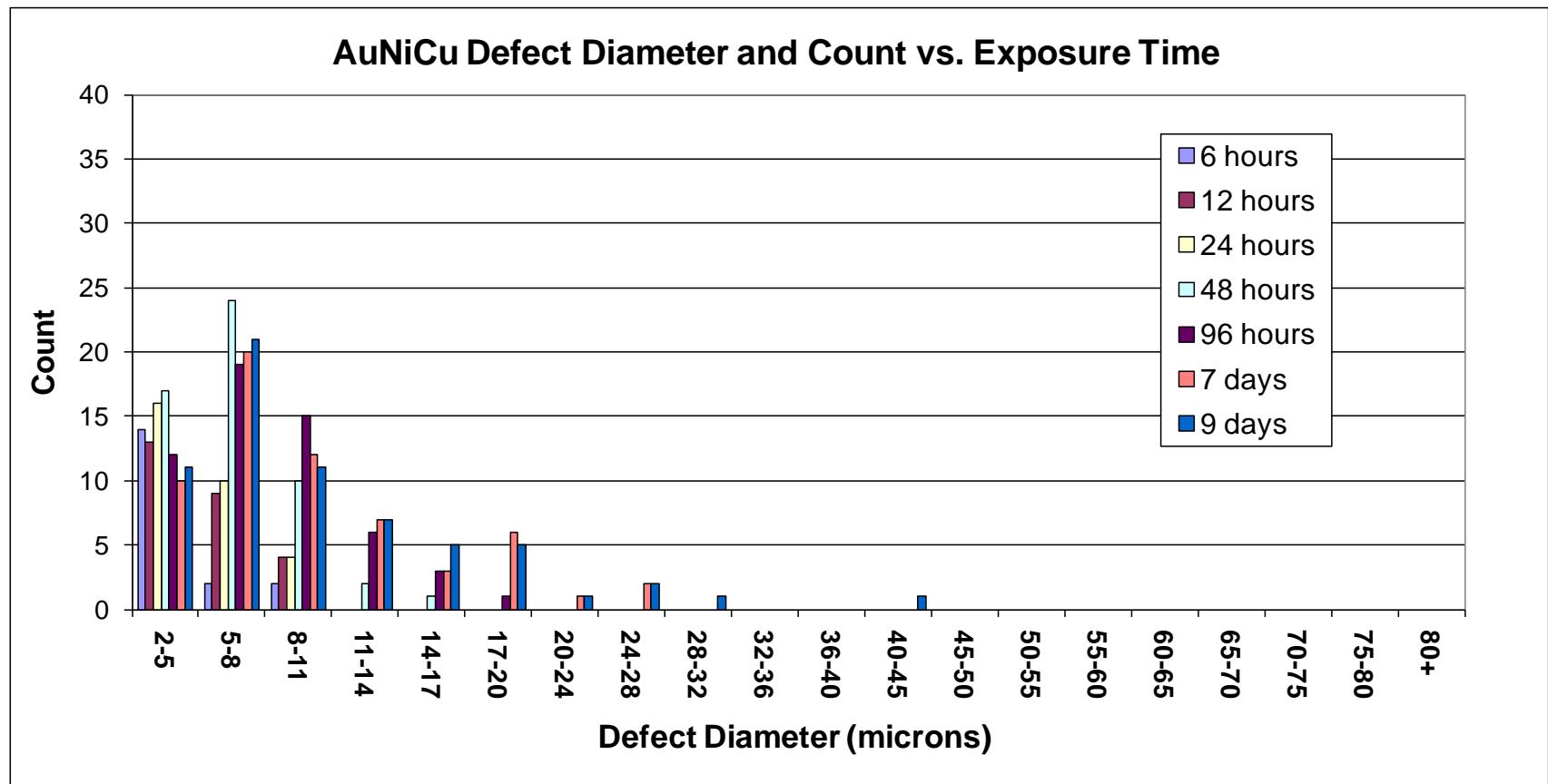


Image Analysis – Defect Size Distribution vs. Time Au:Ni:Cu Samples

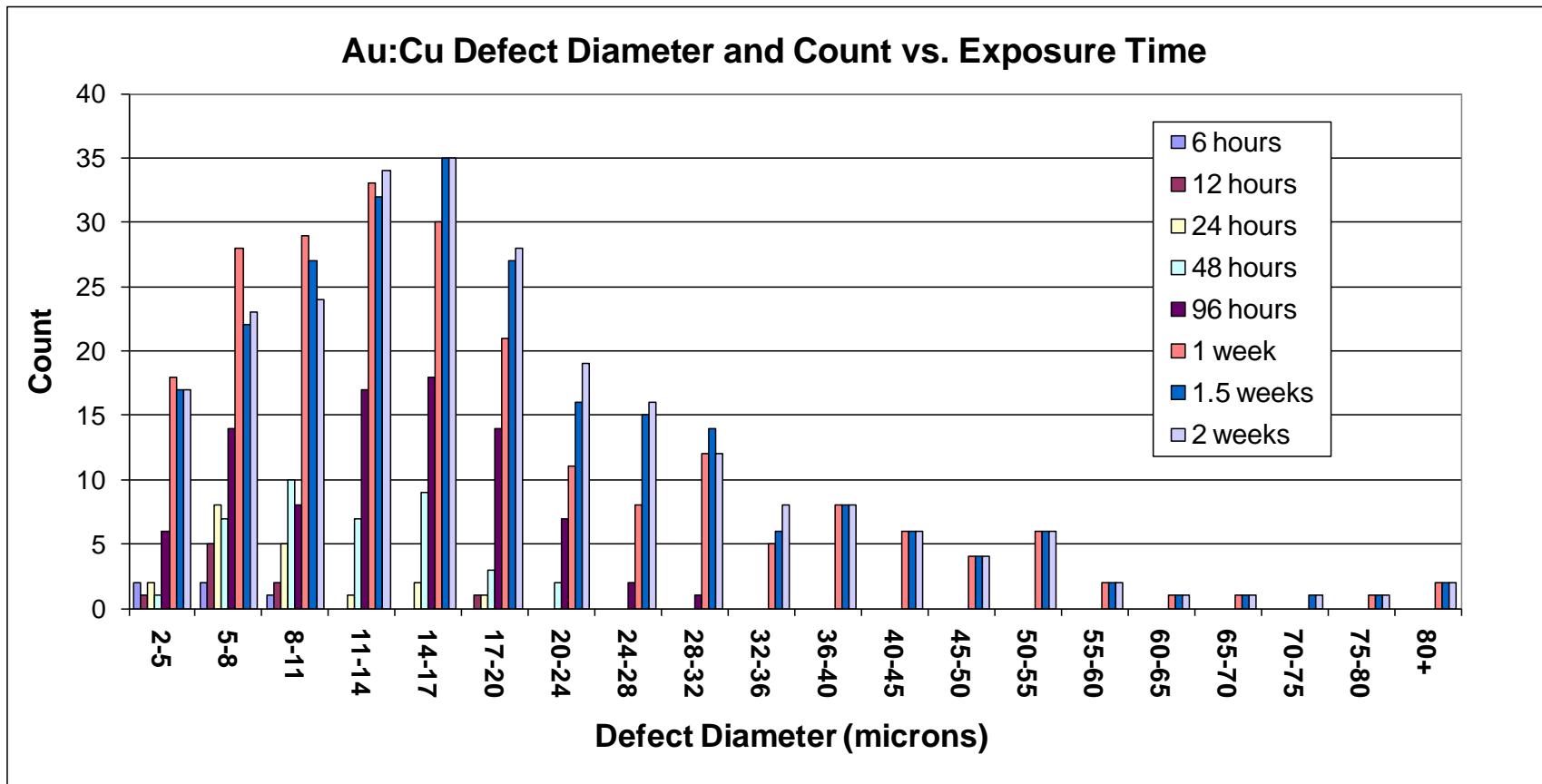
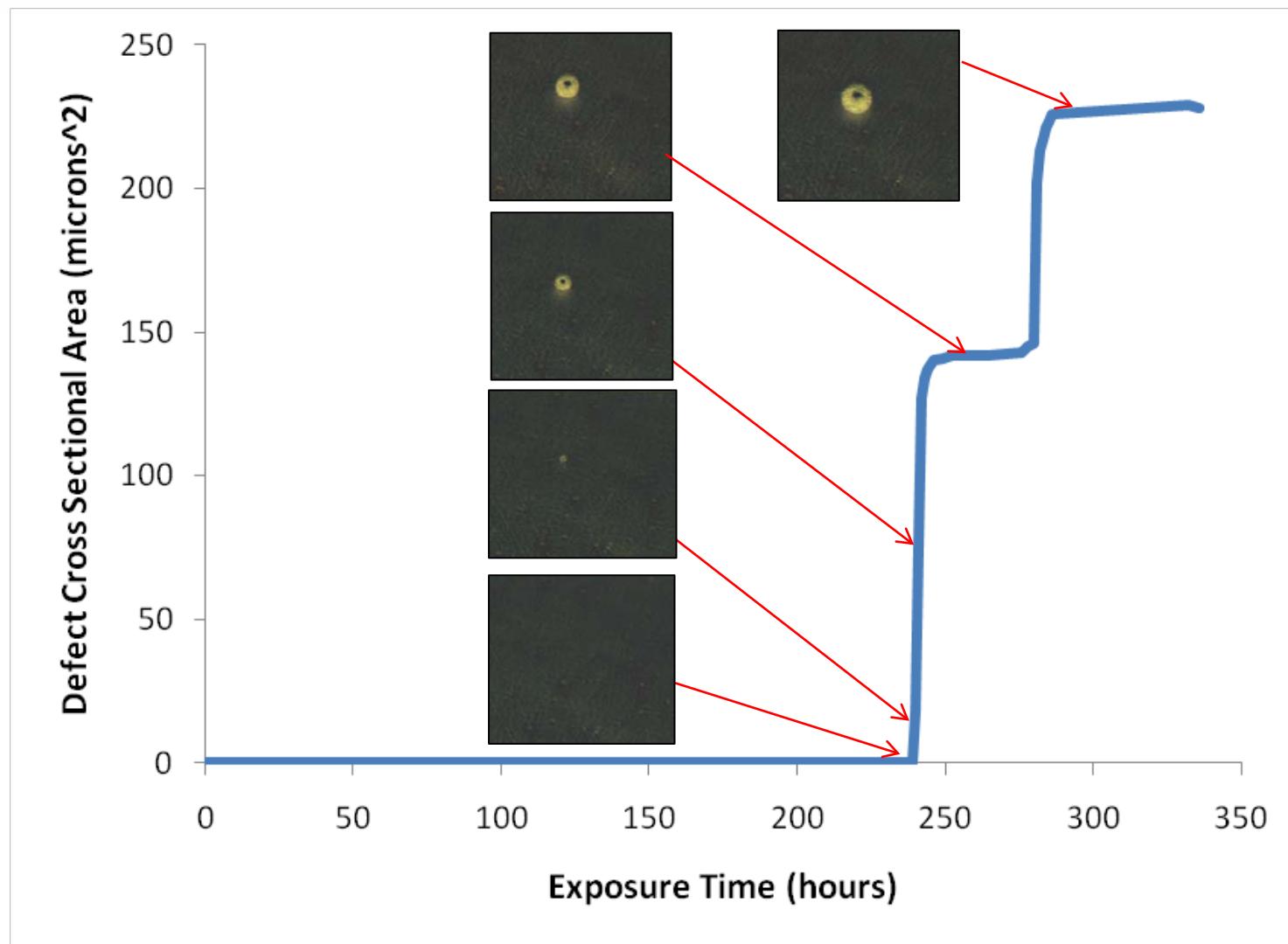


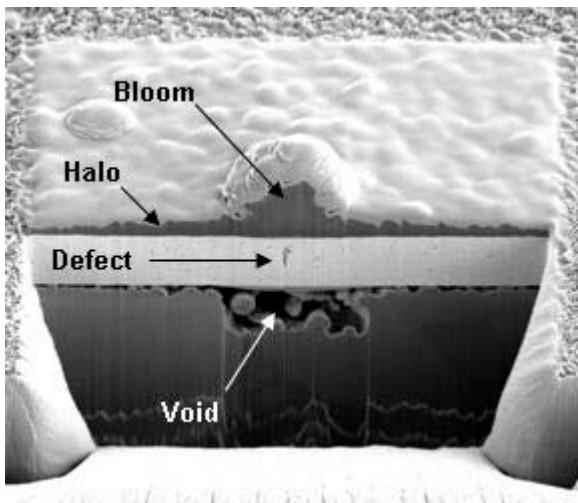
Image Analysis – Individual Defect Size vs. Time

Au:Ni:Cu Sample

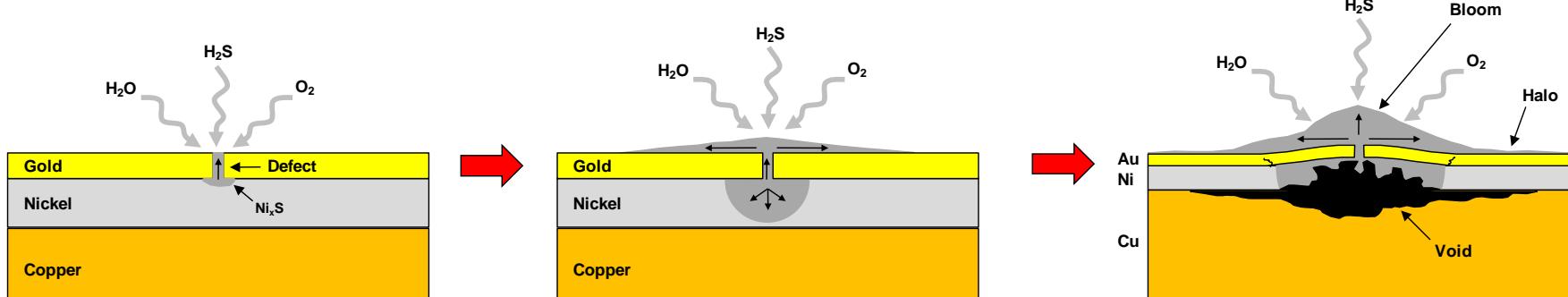
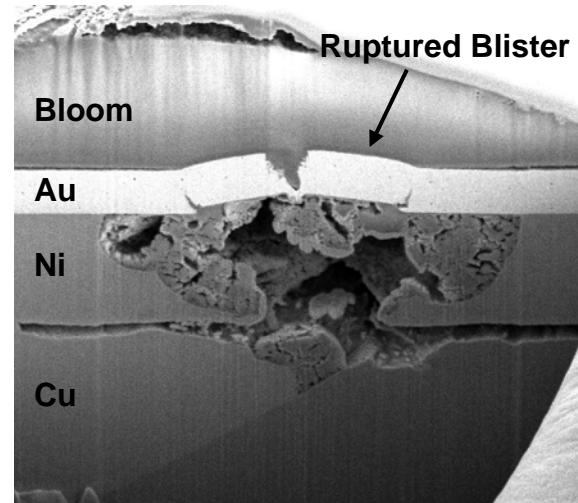


Why Is There A Multi-Stage Growth Process?

Au:Cu



Au:Ni:Cu





Summary/Conclusions

- **Differential imaging system has been developed which enables samples undergoing atmospheric corrosion to be imaged in real time**
 - System functionality demonstrated on noble metal plated copper as used in microelectronic connectors
- **System has provided considerable insight into the sulfidation process for noble metal plated copper**
 - Unbiased measure of corrosion site density and size distribution
 - Time dependent evaluation of corrosion site size
 - Multi-stage growth process revealed
 - While additional work is necessary to confirm, experiments to date agree with mechanism proposed for site nucleation, growth, and passivation/stifling